

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((reflectometry ellipsometry scatterometry spectrometry) and t-topping and (reticle photomask mask)).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
L2	0	((reflectometry ellipsometry scatterometry spectrometry) and t-topping).clm.	US-PGPUB	OR	OFF	2006/11/20 10:28
L3	2181	((reflectometry ellipsometry scatterometry spectrometry)).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
L4	1	((reflectometry ellipsometry scatterometry spectrometry) and topping).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
L5	0	((reflectometry ellipsometry scatterometry spectrometry) and fotting).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
L6	1	((reflectometry ellipsometry scatterometry spectrometry) and footing).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
L7	0	(t-topping and (reticle photomask mask)).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
L8	4	(topping and (reticle photomask mask)).clm.	US-PGPUB	OR	OFF	2006/11/20 10:29
S2	255	(382/144).CCLS.	USPAT	OR	OFF	2006/05/31 10:28
S3	9802	reticle	USPAT	OR	OFF	2005/06/22 10:50
S4	99	S2 and S3	USPAT	OR	OFF	2005/06/22 10:50
S5	192369	(reticle mask)	USPAT	OR	ON	2005/07/15 13:05
S7	13355	(feedforward\$3 feed near1 forward\$3 feed-forward\$3)	USPAT	OR	ON	2005/06/22 10:52
S8	4	S2 and S7	USPAT	OR	ON	2005/06/22 10:55
S9	482	advance near2 control near2 system	USPAT	OR	ON	2005/07/13 09:16
S10	0	S2 and S9	USPAT	OR	ON	2005/06/22 10:55
S11	3	("6458605" "6509201" "6529282").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/22 11:01
S12	2	("6665065" "6674522").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/22 11:02
S13	255	(382/144).CCLS.	USPAT	OR	OFF	2005/07/13 09:05
S14	193200	(reticle mask)	USPAT	OR	ON	2005/07/13 09:05
S15	231	S13 and S14	USPAT	OR	ON	2005/07/13 10:33

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S16	100	(improv\$3 correct\$3 better refin\$3 revis\$3) near3 fabrication with tolerance	USPAT	OR	ON	2005/07/13 09:11
S17	0	S15 and S16	USPAT	OR	ON	2005/07/13 09:11
S18	171	(improv\$3 correct\$3 better refin\$3 revis\$3) near3 fabrication same tolerance	USPAT	OR	ON	2005/07/13 09:46
S19	0	S15 and S18	USPAT	OR	ON	2005/07/13 09:12
S20	10622	((run-to-run run adj to adj run) near3 control\$3) fault near3 detection classification near3 control\$3	USPAT	OR	ON	2005/07/13 09:14
S22	0	"10/676,613".app.	US-PGPUB; USPAT	OR	ON	2005/07/13 09:15
S23	187	advance near2 process near2 control	USPAT	OR	ON	2005/12/05 10:13
S24	221	r2r	USPAT	OR	ON	2005/07/13 09:20
S26	6697	(improv\$3 correct\$3 better refin\$3 revis\$3) near3 fabrication	USPAT	OR	ON	2005/07/13 09:46
S27	8	S26 and S15	USPAT	OR	ON	2005/07/13 09:46
S28	2	("6665065" "6674522").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/07/13 09:59
S29	9	("4716299" "5796484" "5900354" "5940175" "5989763" "6097790" "6279249" "6327021" "6363166").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/07/13 10:19
S30	1	("4,926,489").PN.	USPAT	OR	OFF	2005/07/13 10:32
S31	176	future near3 S14	USPAT	OR	OFF	2005/07/13 10:32
S32	0	S15 and S31	USPAT	OR	OFF	2005/07/13 10:32
S33	12573	neural near2 network evolutionary near2 program\$4 memory near2 bas\$3 near2 reason\$3 decision near2 tree genetic near2 algorithm bayseian	USPAT	OR	ON	2005/07/13 10:34
S35	3	S15 and S33	USPAT	OR	ON	2005/07/13 10:38
S36	7644	correct\$4 near3 defect\$3	USPAT	OR	ON	2005/07/13 10:38
S37	35	S15 and S36	USPAT	OR	ON	2005/07/13 12:47
S38	5	((("4148065") or ("6396943") or ("5798193") or ("6016357") or ("6091845"))).PN.	USPAT	OR	OFF	2005/07/13 12:47

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S39	20	("4628531" "4633504" "4641353" "4669123" "4958374" "5293557" "5307421" "5475766" "5481624" "5513275" "5572598" "5582939" "5621652" "5801954" "5804340" "5849440" "5889678" "5889686" "6014456" "6023328").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/07/15 12:39
S40	1	("5787190").PN.	USPAT	OR	OFF	2005/07/15 13:05
S41	25977	(reticle mask) with resist	USPAT	OR	ON	2005/07/15 13:05
S42	447	(reticle mask) with resist same (PMMA EBR-9 PBS ZEP AZ5206 APxe-e Uv-5)	USPAT	OR	ON	2005/07/15 15:27
S44	231	(reticle mask) with resist with (PMMA EBR-9 PBS ZEP AZ5206 APxe-e Uv-5)	USPAT	OR	ON	2005/07/15 13:11
S45	60	(reticle) with resist with (PMMA EBR-9 PBS ZEP AZ5206 APxe-e Uv-5)	USPAT	OR	ON	2005/07/15 13:18
S46	36	fabrication with (reticle) with resist	USPAT	OR	ON	2005/07/15 13:32
S47	0	"10/676,613".app.	US-PGPUB; USPAT	OR	ON	2006/05/31 10:36
S48	1	submicron near2 develop\$5 near2 center	US-PGPUB; USPAT	OR	ON	2005/07/15 14:38
S49	0	(PMMA EBR-9 PBS ZEP AZ5206 APxe-e Uv-5)	USPAT	AND	ON	2005/07/15 15:28
S50	1	(PMMA EBR-9 PBS ZEP AZ5206)	USPAT	AND	ON	2005/07/15 15:28
S51	26	advance adj1 process adj1 control	USPAT	OR	ON	2005/12/05 10:16
S52	34	advance adj1 process\$3 adj1 control\$3	USPAT	OR	ON	2005/12/05 10:39
S53	429	advance\$2 adj1 process\$3 adj1 control\$3	USPAT	OR	ON	2005/12/05 10:40
S54	405	advanced adj1 process\$3 adj1 control\$3	USPAT	OR	ON	2005/12/05 10:40
S55	344	advanced adj1 process\$3 adj1 control\$3 and (reticle mask semiconductor)	USPAT	OR	ON	2005/12/05 10:40
S56	371	scatterometry	USPAT	OR	OFF	2006/05/31 10:28
S57	255	scatterometry and critical near3 dimension	USPAT	OR	ON	2006/05/31 10:28
S58	148	scatterometry same critical near3 dimension	USPAT	OR	ON	2006/05/31 10:29

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S59	47	scatterometry same critical near3 dimension and reticle	USPAT	OR	ON	2006/05/31 10:30
S60	108	scatterometry same critical near3 dimension and (reticle mask)	USPAT	OR	ON	2006/05/31 10:34
S61	134	(scatterometer scatterometry spectrometry) same critical near3 dimension and (reticle mask)	USPAT	OR	ON	2006/05/31 10:37
S62	0	"10/676,613".app.	US-PGPUB; USPAT	OR	ON	2006/05/31 10:36
S63	136	(scatterometer scatterometry spectrometry) same critical near3 dimension and (reticle mask photomask)	USPAT	OR	ON	2006/05/31 10:39
S64	8	(scatterometer scatterometry spectrometry) same critical near3 dimension and (reticle mask photomask) and ((improv\$3 correct\$3 better refin\$3 revis\$3) near3 fabrication)	USPAT	OR	ON	2006/05/31 10:40
S65	23	(scatterometer scatterometry spectrometry) and critical near3 dimension and (reticle mask photomask) and ((improv\$3 correct\$3 better refin\$3 revis\$3) near3 fabrication)	USPAT	OR	ON	2006/05/31 10:55
S67	0	"09/911238".app.	US-PGPUB	OR	ON	2006/05/31 10:55
S68	5	("20020140930" "5774222" "5923432" "6081325" "6292260").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/05/31 10:59
S69	8	("20020050160" "20020155389" "20030000922" "4435441" "6342265" "6423457" "6448097" "6489624").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/05/31 12:07
S70	3	("6458605" "6509201" "6529282").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/05/31 12:22
S71	1	("6778268").PN.	USPAT	OR	OFF	2006/11/16 13:48
S72	1	("6884552").PN.	USPAT	OR	OFF	2006/11/16 13:49
S73	0	(reflectometry ellipsometry scatterometry) with topping	USPAT	OR	OFF	2006/11/16 13:50
S74	2	(reflectometry ellipsometry scatterometry) same topping	USPAT	OR	OFF	2006/11/16 13:52
S75	2	(reflectometry ellipsometry scatterometry) same t-topping	USPAT	OR	OFF	2006/11/16 13:52

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S76	2	(reflectometry ellipsometry scatterometry spectrometry) same t-topping	USPAT	OR	OFF	2006/11/16 13:52
S77	24	(reflectometry ellipsometry scatterometry spectrometry) and t-topping	USPAT	OR	OFF	2006/11/16 13:53
S78	5	(reflectometry ellipsometry scatterometry spectrometry) and t-topping and (reticle photomask)	USPAT	OR	OFF	2006/11/20 10:28
S79	9	(reflectometry ellipsometry scatterometry spectrometry) and t-topping and (reticle photomask)	USPAT	OR	ON	2006/11/16 13:56
S80	1	("6597463").PN.	USPAT	OR	OFF	2006/11/16 14:04
S81	1	("5801954").PN.	USPAT	OR	OFF	2006/11/16 14:08
S82	1	("6721691").PN.	USPAT	OR	OFF	2006/11/16 14:08